Notice of References Cited Application/Control No. 10/575,908 Applicant(s)/Patent Under Reexamination JUNEAU, J. RENE Examiner Art Unit Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0092015	07-2002	Sprunk et al.	725/9
*	В	US-5,867,226	02-1999	Wehmeyer et al.	725/46
*	C	US-2002/0104083	08-2002	Hendricks et al.	725/34
*	D	US-2004/0123329	06-2004	Williams et al.	725/111
*	Е	US-6,009,116	12-1999	Bednarek et al.	375/130
*	F	US-6,381,747	04-2002	Wonfor et al.	725/104
*	G	US-6,035,037	03-2000	Chaney, John William	380/227
*	Η	US-6,177,931	01-2001	Alexander et al.	725/52
*	I	US-2004/0055010	03-2004	Fries et al.	725/060
*	J	US-2003/0097657	05-2003	Zhou et al.	725/46
*	К	US-2004/0194124	09-2004	Medvinsky, Alexander	725/025
	L	US-			
_	М	US-			

FOREIGN PATENT DOCUMENTS

	*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
Cha	inge	(s _N) a	p##2d00244284 A	09-2000	Japan	SUZUKI, KEIJI	H03J 07/18
to c	ocu	mont	, W O 2054765 A1	07-2002	World Intellect	TSURIA et al.	H04N 07/16
/S.	R.R	·P	WO 02/054765				
3/1	0/2	Q					
		R					
		Ø					
	·	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	J	Machine Translation of JP 2000244284 A			
	>				
	W				
	×				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.